ATTY DOCKET NO.	SERIAL NO.
ITL.1026US (P16713)	10/688,521
APPLICANT(S): Robert P. Meagley et al.	
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INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
MM	A.	6,162,592	12/19/2000	Taylor et al.			
	B.						
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	I.						
	J.						

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	O.							

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MM	P.	Lin et al., *Line Edge Roughness in Positive-Tone Chemically Amplified Resists: Effect of Additives and Processing Conditions*, Proceedings of the SPIE - The International Society for Optical Engineering, Vol. 4345, No. 1, Feb. 2001, pgs. 78-86.
	Q.	
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	S.	
	T.	
	U.	

EXAMINER	DATE CONSIDERED
Mark C Ware	January 18, 2006

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.